

SCCS048 - March 1997 - Revised March 2000

### **Features**

- Low power, pin-compatible replacement for LCX and LPT families
- 5V tolerant inputs and outputs
- · 24 mA balanced drive outputs
- · Power-off disable outputs permits live insertion
- · Edge-rate control circuitry for reduced noise
- FCT-C speed at 4.4 ns
- Latch-up performance exceeds JEDEC standard no. 17
- Typical output skew < 250 ps
- Industrial temperature range of -40°C to +85°C
- TSSOP (19.6-mil pitch) or SSOP (25-mil pitch)
- Typical V<sub>olp</sub> (ground bounce) performance exceeds Mil Std 883D
- V<sub>CC</sub> = 2.7V to 3.6V
- ESD (HBM) > 2000V

### CY74FCT163H952

- · Bus hold on data inputs
- Eliminates the need for external pull-up or pull-down resistors
- Devices with bus hold are not recommended for translating rail-to-rail CMOS signals to 3.3V logic levels

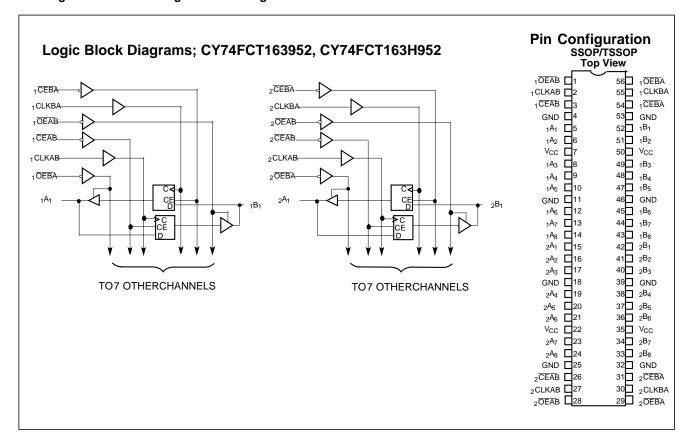
# 16-Bit Registered Transceivers

## **Functional Description**

These 16-bit registered transceivers are high-speed, low-power devices. 16-bit operation is achieved by connecting the control lines of the two 8-bit registered transceivers together. For data flow from bus A-to-B, CEAB must be LOW to allow data to be stored when CLKAB transitions from LOW-to-HIGH. The stored data will be present on the output when OEAB is LOW. Control of data from B-to-A is similar and is controlled by using the CEBA, CLKBA, and OEBA inputs. The outputs are 24-mA balanced output drivers with current limiting resistors to reduce the need for external terminating resistors and provide for minimal undershoot and reduced ground bounce.

The CY74FCT163H952 has "bus hold" on the data inputs, which retains the input's last state whenever the source driving the input goes to high impedance. This eliminates the need for pull-up/down resistors and prevents floating inputs.

The CY74FCT163952 is designed with inputs and outputs capable of being driven by 5.0V buses, allowing its use in mixed voltage systems as a translator. The outputs are also designed with a power off disable feature enabling its use in applications requiring live insertion.





## **Pin Description**

Name	Description				
OEAB	A-to-B Output Enable Input (Active LOW)				
OEBA	B-to-A Output Enable Input (Active LOW)				
CEAB	A-to-B Clock Enable Input (Active LOW)				
CEBA	B-to-A Clock Enable Input (Active LOW)				
CLKAB	A-to-B Clock Input				
CLKBA	B-to-A Clock Input				
А	A-to-B Data Inputs or B-to-A Three-State Outputs <sup>[1]</sup>				
В	B-to-A Data Inputs or A-to-B Three-State Outputs <sup>[1]</sup>				

## Function Table<sup>[2, 3]</sup>

For A-to-B (Symmetric with B-to-A)

	Inputs						
CEAB	CLKAB	OEAB	Α	В			
Н	Х	L	Х	B <sup>[4]</sup>			
Х	L	L	Х	B <sup>[4]</sup>			
L	7	L	L	L			
L	7	L	Н	Н			
Х	Х	Н	Х	Z			

## Maximum Ratings<sup>[5, 6]</sup>

(Above which the useful life may be impaired. For user guidelines, not tested.)
Storage Temperature55°C to +125°C
Ambient Temperature with Power Applied–55°C to +125°C
Supply Voltage Range
DC Input Voltage0.5V to +7.0V
DC Output Voltage0.5V to +7.0V
DC Output Current (Maximum Sink Current/Pin)60 to +120 mA
Power Dissipation

## **Operating Range**

Range	Ambient Temperature	V <sub>CC</sub>
Industrial	–40°C to +85°C	2.7V to 3.6V

## Electrical Characteristics for Non Bus Hold Devices Over the Operating Range V<sub>CC</sub>=2.7V to 3.6V

Parameter	Description	Test Condi	Test Conditions		Typ. <sup>[7]</sup>	Max.	Unit
V <sub>IH</sub>	Input HIGH Voltage	All Inputs		2.0		5.5	V
$V_{IL}$	Input LOW Voltage					0.8	V
V <sub>H</sub>	Input Hysteresis <sup>[8]</sup>				100		mV
V <sub>IK</sub>	Input Clamp Diode Voltage	V <sub>CC</sub> =Min., I <sub>IN</sub> =–18 i	mA		-0.7	-1.2	V
I <sub>IH</sub>	Input HIGH Current	V <sub>CC</sub> =Max., V <sub>I</sub> =5.5				±1	μΑ
I <sub>IL</sub>	Input LOW Current	V <sub>CC</sub> =Max., V <sub>I</sub> =GND				±1	μΑ
l <sub>OZH</sub>	High Impedance Output Current (Three-State Output pins)	V <sub>CC</sub> =Max., V <sub>OUT</sub> =5.5V				±1	μΑ
I <sub>OZL</sub>	High Impedance Output Current (Three-State Output pins)	V <sub>CC</sub> =Max., V <sub>OUT</sub> =GND				±1	μΑ
I <sub>OS</sub>	Short Circuit Current <sup>[9]</sup>	V <sub>CC</sub> =Max., V <sub>OUT</sub> =G	SND	-60	-135	-240	mA
l <sub>OFF</sub>	Power-Off Disable	V <sub>CC</sub> =0V, V <sub>OUT</sub> ≤4.5\	V			±100	μΑ
I <sub>CC</sub>	Quiescent Power Supply Current	V <sub>IN</sub> ≤0.2V, V <sub>IN</sub> ≥V <sub>CC</sub> −0.2V	V <sub>CC</sub> =Max.		0.1	10	μΑ
Δl <sub>CC</sub>	Quiescent Power Supply Current (TTL inputs HIGH)	V <sub>IN</sub> =V <sub>CC</sub> -0.6V <sup>[10]</sup>	V <sub>CC</sub> =Max.		2.0	30	μΑ

### Notes:

- Notes:

   On the CY74FCT163H952, these pins have bus hold.
   A-to-B data flow is shown: B-to-A data flow is similar but uses, CEBA, CLKBA, and OEBA.
   H = HIGH Voltage Level. L = LOW Voltage Level. X = Don't Care. J= LOW-to-HIGH Transition. Z = HIGH Impedance.

   Level of B before the indicated steady-state input conditions were established.
   Operation beyond the limits set forth may impair the useful life of the device. Unless otherwise noted, these limits are over the operating free-air temperature.
   With the exception of inputs with bus hold, unused inputs must always be connected to an appropriate logic voltage level, preferably either V<sub>CC</sub> or ground,
   Typical values are at V<sub>CC</sub>=3.3V, T<sub>A</sub> = +25°C ambient.

   Not more than one output should be shorted at a time. Duration of short should not exceed one second. The use of high-speed test apparatus and/or sample and hold techniques are preferable in order to minimize internal chip heating and more accurately reflect operational values. Otherwise prolonged shorting of a high output may raise the chip temperature well above normal and thereby cause invalid readings in other parametric tests. In any sequence of parameter tests, I<sub>OS</sub> tests should be performed last.
   Per TTL driven input; all other inputs at V<sub>CC</sub> or GND.



## Electrical Characteristics For Bus Hold Devices Over the Operating Range $V_{CC}$ =2.7V to 3.6V

Parameter	Description	Test Condi	tions	Min.	<b>Typ.</b> <sup>[7]</sup>	Max.	Unit
V <sub>IH</sub>	Input HIGH Voltage	All Inputs		2.0		V <sub>CC</sub>	V
V <sub>IL</sub>	Input LOW Voltage					0.8	٧
$V_{H}$	Input Hysteresis <sup>[8]</sup>				100		mV
V <sub>IK</sub>	Input Clamp Diode Voltage	V <sub>CC</sub> =Min., I <sub>IN</sub> =–18	mA		-0.7	- 1.2	V
I <sub>IH</sub>	Input HIGH Current	V <sub>CC</sub> =Max., V <sub>I</sub> =V <sub>CC</sub>				±100	μΑ
I <sub>IL</sub>	Input LOW Current					±100	μΑ
I <sub>BBH</sub>	Bus Hold Sustain Current on Bus Hold Input <sup>[11]</sup>	V <sub>CC</sub> =Min.	V <sub>I</sub> =2.0V	-50			μΑ
I <sub>BBL</sub>			V <sub>I</sub> =0.8V	+50			μΑ
I <sub>BHHO</sub> I <sub>BHLO</sub>	Bus Hold Overdrive Current on Bus Hold Input <sup>[11]</sup>	V <sub>CC</sub> =Max., V <sub>I</sub> =1.5	V			±500	μА
I <sub>OZH</sub>	High Impedance Output Current (Three-State Output pins)	V <sub>CC</sub> =Max., V <sub>OUT</sub> =V <sub>CC</sub>				±1	μΑ
I <sub>OZL</sub>	High Impedance Output Current (Three-State Output pins)	V <sub>CC</sub> =Max., V <sub>OUT</sub> =	GND			±1	μΑ
Ios	Short Circuit Current <sup>[9]</sup>	V <sub>CC</sub> =Max., V <sub>OUT</sub> =GND		-60	-135	-240	mA
I <sub>OFF</sub>	Power-Off Disable	V <sub>CC</sub> =0V, V <sub>OUT</sub> ≤4.5V				±100	μΑ
I <sub>CC</sub>	Quiescent Power Supply Current	V <sub>IN</sub> ≤0.2V V <sub>CC</sub> V <sub>IN</sub> ≥V <sub>CC</sub> −0.2V	V <sub>CC</sub> =Max.			+40	μΑ
$\Delta_{ICC}$	Quiescent Power supply Current (TTL inputs HIGH)	V <sub>IN</sub> =V <sub>CC</sub> -0.6V <sup>[10]</sup>	V <sub>CC</sub> =Max.			+350	μΑ

## Electrical Characteristics For Balanced Drive Devices Over the Operating Range $V_{CC}$ =2.7V to 3.6V

Parameter	Description	Test Conditions	Min.	<b>Typ.</b> <sup>[7]</sup>	Max.	Unit
I <sub>ODL</sub>	Output LOW Dynamic Current <sup>[9]</sup>	$V_{CC}$ =3.3V, $V_{IN}$ = $V_{IH}$ or $V_{IL}$ , $V_{OUT}$ =1.5V	50	90	200	mA
I <sub>ODH</sub>	Output HIGH Dynamic Current <sup>[9]</sup>	$V_{CC}$ =3.3V, $V_{IN}$ = $V_{IH}$ or $V_{IL}$ , $V_{OUT}$ =1.5V	-36	-60	-110	mA
V <sub>OH</sub>	Output HIGH Voltage	V <sub>CC</sub> =Min., I <sub>OH</sub> = -0.1 mA	V <sub>CC</sub> -0.2			V
		V <sub>CC</sub> =Min., I <sub>OH</sub> = -8 mA	2.4 <sup>[12]</sup>	3.0		V
		V <sub>CC</sub> =3.0V, I <sub>OH</sub> = -24 mA	2.0	3.0		V
V <sub>OL</sub>	Output LOW Voltage	V <sub>CC</sub> =Min., I <sub>OL</sub> = 0.1mA			0.2	V
		V <sub>CC</sub> =Min., I <sub>OL</sub> = 24 mA		0.3	0.55	

Notes:

11. Pins with bus hold are described in Pin Description.

12. V<sub>OH</sub>=V<sub>CC</sub>-0.6 V at rated current

# $\textbf{Capacitance}^{[8]}(T_{A}=+25^{\circ}C,\,f=1.0\;\text{MHz})$

Parameter	Description	Test Conditions	Typ. <sup>[7]</sup>	Max.	Unit
C <sub>IN</sub>	Input Capacitance	$V_{IN} = 0V$	4.5	6.0	pF
C <sub>OUT</sub>	Output Capacitance	V <sub>OUT</sub> = 0V	5.5	8.0	pF



## **Power Supply Characteristics**

Parameter	Description	Test Condition	ons	<b>Typ.</b> <sup>[7]</sup>	Max.	Unit
I <sub>CCD</sub>	Dynamic Power Supply Current <sup>[13]</sup>	V <sub>CC</sub> =Max., One Input Toggling, 50% Duty Cycle, Outputs Open, OE=GND	V <sub>IN</sub> =V <sub>CC</sub> or V <sub>IN</sub> =GND	50	75	μΑ/MHz
I <sub>C</sub>	Total Power Supply Current <sup>[14]</sup>	Duty Cycle, Outputs Open, One	V <sub>IN</sub> =V <sub>CC</sub> or V <sub>IN</sub> =GND	0.5	0.8	mA
		Bit Toggling, OE=GND	V <sub>IN</sub> =V <sub>CC</sub> -0.6V or V <sub>IN</sub> =GND	0.5	0.8	mA
Duty Cycle, Outputs Open		Duty Cycle, Outputs Open, Six-	V <sub>IN</sub> =V <sub>CC</sub> or V <sub>IN</sub> =GND	2.0	3.0 <sup>[15]</sup>	mA
		teen Bits Toggling, OE=GND	V <sub>IN</sub> =V <sub>CC</sub> -0.6V or V <sub>IN</sub> =GND	2.0	3.3 <sup>[15]</sup>	mA

## Switching Characteristics Over the Operating Range $V_{CC}$ =3.0V to 3.6V $^{[16,17]}$

					Г163952С 163Н952С			
Parameter	Description	Min.	Max.	Min.	Max.	Unit	Fig. No. <sup>[18]</sup>	
t <sub>PLH</sub> t <sub>PHL</sub>	Propagation Delay Data to Output	1.5	4.8	1.5	4.4	ns	1, 3	
t <sub>PZH</sub>	Output Enable Time	1.5	6.2	1.5	5.8	ns	1, 7, 8	
t <sub>PHZ</sub> t <sub>PLZ</sub>	Output Disable Time	1.5	5.6	1.5	5.2	ns	1, 7, 8	
t <sub>SK(O)</sub>	Output Skew <sup>[19]</sup>		0.5		0.5	ns	_	

### Notes:

- This parameter is not directly testable, but is derived for use in Total Power Supply calculations.  $\begin{matrix} I_C &=& I_{QUIESCENT} + I_{INPUTS} + I_{DYNAMIC} \\ I_C &=& I_{CC} + \Delta I_{CC} D_H N_T + I_{CCD} (f_0/2 + f_1 N_1) \\ I_{CC} &=& Quiescent Current with CMOS input levels \end{matrix}$

 $\Delta I_{CC}$  = Power Supply Current for a TTL HIGH input (V<sub>IN</sub>=3.4V)

 $\begin{array}{lll} \text{Disc} & \text{Fower supply cutterfit in Park N} \\ \text{D}_{\text{H}} & = & \text{Duty Cycle for TTL inputs HIGH} \\ \text{N}_{\text{T}} & = & \text{Number of TTL inputs at D}_{\text{H}} \\ \text{I}_{\text{CCD}} & = & \text{Dynamic Current caused by an input transition pair (HLH or LHL)} \\ \text{f}_{0} & = & \text{Clock frequency for registered devices, otherwise zero} \end{array}$ 

= Input signal frequency

= Number of inputs changing at f<sub>1</sub>

- All currents are in milliamps and all frequencies are in megahertz. Values for these conditions are examples of the l<sub>CC</sub> formula. These limits are specified but not tested.

- Values for triese conditions are examples of the I<sub>CC</sub> formula. These limits are specified but not tested.
   Minimum limits are specified but not tested on Propagation Delays.
   For V<sub>CC</sub> =2.7, propagation delay, output enable and output disable times should be degraded by 20%.
   See "Parameter Measurement Information" in the General Information section.
   Skew between any two outputs of the same package switching in the same direction. This parameter is ensured by design.

### Ordering Information CY74FCT163952

Speed (ns)	Ordering Code	Package Name	Package Type	Operating Range
4.1	CY74FCT163952CPACT	Z48	48-Lead (240-Mil) TSSOP	Industrial
	CY74FCT163952CPVC/PVCT	O48	48-Lead (300-Mil) SSOP	
4.8	CY74FCT163952APVC/PVCT	O48	48-Lead (300-Mil) SSOP	Industrial

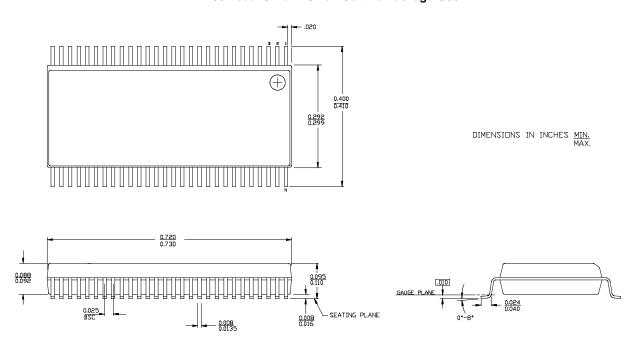
### Ordering Information CY74FCT163H952

Speed (ns)	Ordering Code	Package Name	Package Type	Operating Range
4.1	74FCT163H952CPACT	Z48	48-Lead (240-Mil) TSSOP	Industrial
	CY74FCT163H952CPVC	O48	48-Lead (300-Mil) SSOP	
	74FCT163H952CPVCT	O48	48-Lead (300-Mil) SSOP	

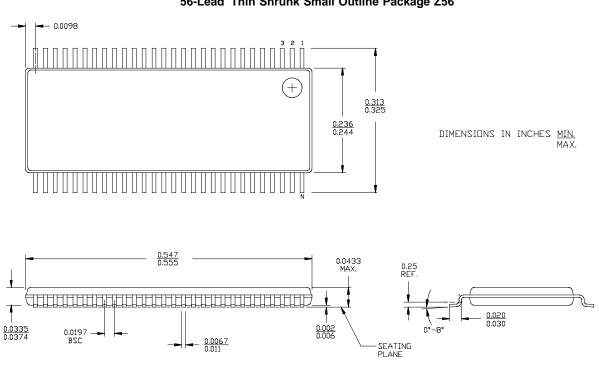


## **Package Diagrams**

## 56-Lead Shrunk Small Outline Package O56



## 56-Lead Thin Shrunk Small Outline Package Z56



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